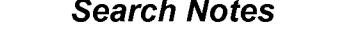


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/580,288	SHENG ET AL.	
	<b>Examiner</b> PHUOC H. DOAN	<b>Art Unit</b> 2617	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
See Attached Interference Search History		12/3/2008	PHD